

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s) : Martin R. Elliott et al.

Serial No. :

10/650,312

Filed

: August 28, 2003

For

METHOD AND APPARATUS FOR USING SUBSTRATE

CARRIER MOVEMENT TO ACTUATE SUBSTRATE

CARRIER DOOR OPENING/CLOSING

Group Art Unit: 3652

Customer No. : 41161

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Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In accordance with 37 C.F.R. §§ 1.56 and 1.97, applicants wish to call the attention of the Examiner to the following references:

- U.S. Patent No. 5,372,471, Wu
- U.S. Patent No. 4,027,246, Caccoma et al.
- U.S. Patent No. 6,082,948, Fishkin et al.
- U.S. Patent No. 5,888,042, Oda
- U.S. Patent No. 6,048,259, Asai

- U.S. Patent No. 3,845,286, Aronstein et al.
- U.S. Patent No. 6,026,561, Lafond
- U.S. Patent No. 5,884,392, Lafond
- U.S. Patent No. 5,411,358, Garric et al.
- U.S. Patent No. 5,382,127, Garric et al.
- U.S. Patent No. 4,166,527, Beezer
- U.S. Patent No. 5,818,716, Chin et al.
- U.S. Patent No. 5,612,886, Weng
- U.S. Patent No. 5,976,199, Wu et al.
- U.S. Patent No. 5,256,204, Wu
- Foreign Art Reference No. JP 08-046005 (Japan)
- Foreign Art Reference No. JP 11-121585 (Japan)
- Foreign Art Reference No. WO 97/03001 A1 (PCT)
- Foreign Art Reference No. WO 98/50946 A1 (PCT)
- Foreign Art Reference No. WO 99/28952 A2 (PCT)
- Foreign Art Reference No. WO 00/44653 A1 (PCT)
- Foreign Art Reference No. WO 00/59004 A1 (PCT)
- Foreign Art Reference No. WO 01/01828 A1 (PCT)
- Foreign Art Reference No. WO 01/10756 A1 (PCT)
- Foreign Art Reference No. WO 02/04774 A2 (PCT)
- Foreign Art Reference No. EP 0513651 A1 (EPO)
- Foreign Art Reference No. EP 0219826 B1 (EPO)
- Foreign Art Reference No. EP 0472536 B1 (EPO)
- Foreign Art Reference No. EP 0651429 A1 (EPO)

Foreign Art Reference No. EP 0556193 B1 (EPO)

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Weiss, Mitchell, "Evaluating 300-mm Fab Automation Technology Options and Selection Criteria", June 1997, MICRO, Vol. 15, No. 6, pages 65-66, 68, 70, 72, 74, 76, 78-79.

Ebert, et al., "Efficient CFD Modeling of Single-Wafer Semiconductor Fabrication Systems for Closed-Loop Evaluation",

Dec. 1997, Proceedings of the 36th IEEE Conference on Decision and Control, Vol. 1, pages 830-831.

Kobayashi, et al., "Particle Characteristics of 300-mm Minienvironment (FOUP and LPU)", 1999, Proceedings of 1999 IEEE International Symposium on Semiconductor Manufacturing Conference Proceedings, pages 39-42.

No-Author, "PRI Selected By Varian Semiconductor to Supply 300mm Integrated Front-End Buffering Solutions", Feb. 10, 2000, Newswire, Page 7434.

These references are also listed on the accompanying Information Disclosure Statement (Form PTO-1449).

Consideration of the foregoing in relation to this patent application is respectfully requested.

Respectfully Submitted,

Brian M. Dugan, Esq. Registration No 41,720

Dugan & Dugan, PC

Attorneys for Applicants

(914)332-9081

Dated:

U.S. Department of Commerce, Patent and Trademark Office					Docket No.: Serial No.: 6976/Y01/SYNX/SYNX/HMM 10/650,312						
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	F-4	WO 98/50946 A1	11/12/98	PCT					Х		
	F-5	WO 99/28952 A2	06/10/99	PCT			_		X		
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		Weiss, Mitchell, "Evaluating 300-mm Fab Automation Technology Options and Selection Criteria", June 1997, MICRO, Vol. 15, No. 6, pages 65-66, 68, 70, 72, 74, 76, 78-79.									
		Ebert, et al., "Efficient CFD Modeling of Single-Wafer Semiconductor Fabrication Systems for Closed-Loop Evaluation", Dec. 1997, Proceedings of the 36th IEEE Conference on Decision and Control, Vol. 1, pages 830-831.									
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